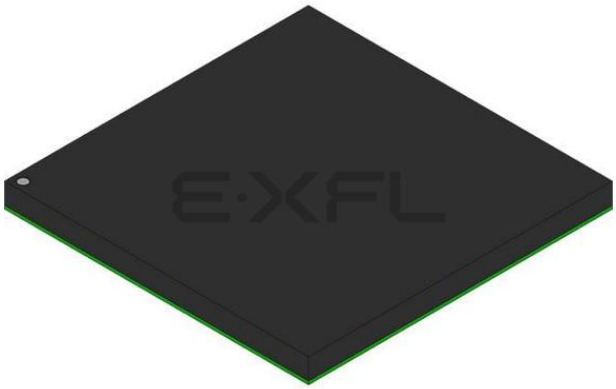

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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	1.333GHz
Co-Processors/DSP	Signal Processing; SPE
RAM Controllers	DDR2, DDR3
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	1023-BFBGA, FCBGA
Supplier Device Package	1023-FCBGA (33x33)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc8572vtauld

Table 9. RESET Initialization Timing Specifications (continued)

PLL config input setup time with stable SYSCLK before $\overline{\text{HRESET}}$ negation	100	—	µs	—
Input setup time for POR configs (other than PLL config) with respect to negation of $\overline{\text{HRESET}}$	4	—	SYSCLKs	1
Input hold time for all POR configs (including PLL config) with respect to negation of $\overline{\text{HRESET}}$	2	—	SYSCLKs	1
Maximum valid-to-high impedance time for actively driven POR configs with respect to negation of $\overline{\text{HRESET}}$	—	5	SYSCLKs	1

Notes:
1. SYSCLK is the primary clock input for the MPC8572E.
2. Reset assertion timing requirements for DDR3 DRAMs may differ.

Table 10 provides the PLL lock times.

Table 10. PLL Lock Times

Parameter/Condition	Symbol	Min	Typical	Max
PLL lock times	—	100	µs	—
Local bus PLL	—	50	µs	—

6 DDR2 and DDR3 SDRAM Controller

This section describes the DC and AC electrical specifications for the DDR2 and DDR3 SDRAM controller interface of the MPC8572E. Note that the required GV_{DD}(typ) voltage is 1.8Vor 1.5 V when interfacing to DDR2 or DDR3 SDRAM, respectively.

6.1 DDR2 and DDR3 SDRAM Interface DC Electrical Characteristics

Table 11 provides the recommended operating conditions for the DDR SDRAM controller of the MPC8572E when interfacing to DDR2 SDRAM.

Table 11. DDR2 SDRAM Interface DC Electrical Characteristics for GV_{DD}(typ) = 1.8 V

Parameter/Condition	Symbol	Min	Max	Unit	Notes
I/O supply voltage	GV_{DD}	1.71	1.89	V	1
I/O reference voltage	$MV_{REF}n$	$0.49 \times GV_{DD}$	$0.51 \times GV_{DD}$	V	2
I/O termination voltage	V_{TT}	$MV_{REF}n - 0.04$	$MV_{REF}n + 0.04$	V	3
Input high voltage	V_{IH}	$MV_{REF}n + 0.125$	$GV_{DD} + 0.3$	V	—
Input low voltage	V_{IL}	–0.3	$MV_{REF}n - 0.125$	V	—
Output leakage current	I_{OZ}	–50	50	µA	4
Output high current (V_{OUT} = 1.420 V)	I_{OH}	–13.4	—	mA	—

Table 18. DDR2 and DDR3 SDRAM Interface Output AC Timing Specifications (continued)

At recommended operating conditions with GV_{DD} of 1.8 V ± 5% for DDR2 or 1.5 V ± 5% for DDR3.

Parameter	Symbol [1]	Min	Max	Unit	Notes
533 MHz		538	—		
400 MHz		700	—		
MDQS preamble start	t_{DDKHMP}			ns	6
800 MHz		$-0.5 \times t_{MCK} - 0.375$	$-0.5 \times t_{MCK} + 0.375$		
<= 667 MHz		$-0.5 \times t_{MCK} - 0.6$	$-0.5 \times t_{MCK} + 0.6$		
MDQS epilogue end	t_{DDKHME}			ns	6
800 MHz		–0.375	0.375		
<= 667 MHz	t_{DDKHME}	–0.6	0.6	ns	6

Note:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. Output hold time can be read as DDR timing (DD) from the rising or falling edge of the reference clock (KH or KL) until the output went invalid (AX or DX). For example, t_{DDKHAS} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes from the high (H) state until outputs (A) are setup (S) or output valid time. Also, t_{DDKLDX} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes low (L) until data outputs (D) are invalid (X) or data output hold time.
2. All MCK/$\overline{\text{MCK}}$ referenced measurements are made from the crossing of the two signals ±0.1 V.
3. ADDR/CMD includes all DDR SDRAM output signals except MCK/$\overline{\text{MCK}}$, $\overline{\text{MCS}}$, and MDQ/MECC/MDM/MDQS.
4. Note that t_{DDKHMH} follows the symbol conventions described in note 1. For example, t_{DDKHMH} describes the DDR timing (DD) from the rising edge of the MCK[n] clock (KH) until the MDQS signal is valid (MH). t_{DDKHMH} can be modified through control of the MDQS override bits (called WR_DATA_DELAY) in the TIMING_CFG_2 register. This typically be set to the same delay as in DDR_SDRAM_CLK_CNTL[CLK_ADJUST]. The timing parameters listed in the table assume that these 2 parameters have been set to the same adjustment value. See the *MPC8572E PowerQUICC™ III Integrated Host Processor Family Reference Manual* for a description and understanding of the timing modifications enabled by use of these bits.
5. Determined by maximum possible skew between a data strobe (MDQS) and any corresponding bit of data (MDQ), ECC (MECC), or data mask (MDM). The data strobe should be centered inside of the data eye at the pins of the microprocessor.
6. All outputs are referenced to the rising edge of MCK[n] at the pins of the microprocessor. Note that t_{DDKHMP} follows the symbol conventions described in note 1.

NOTE

For the ADDR/CMD setup and hold specifications in Table 18, it is assumed that the clock control register is set to adjust the memory clocks by 1/2 applied cycle.

Figure 6 provides the AC test load for the DDR2 and DDR3 Controller bus.

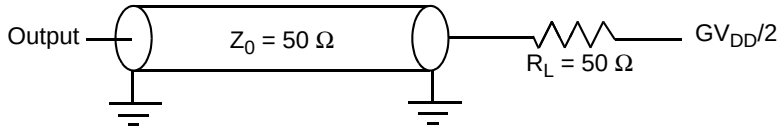
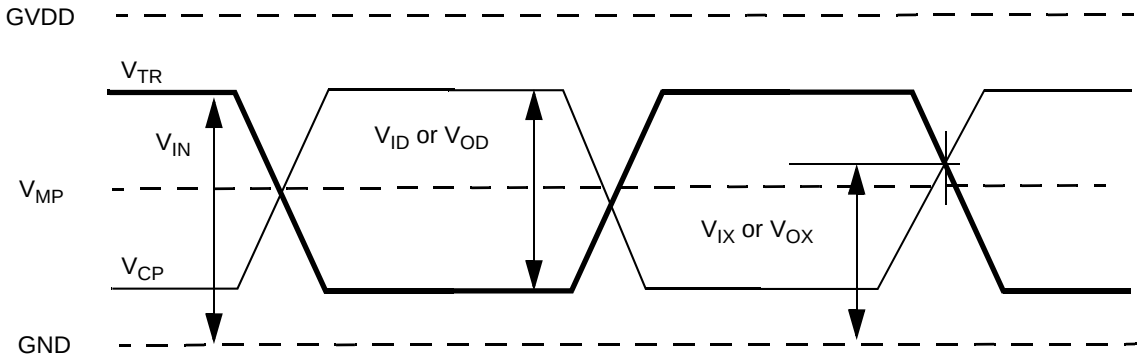


Figure 6. DDR2 and DDR3 Controller bus AC Test Load

6.2.3 DDR2 and DDR3 SDRAM Differential Timing Specifications

This section describes the DC and AC differential electrical specifications for the DDR2 and DDR3 SDRAM controller interface of the MPC8572E.



NOTE

VID specifies the input differential voltage |VTR -VCP| required for switching, where VTR is the true input signal (such as MCK or MDQS) and VCP is the complementary input signal (such as $\overline{\text{MCK}}$ or $\overline{\text{MDQS}}$).

Table 19 provides the differential specifications for the MPC8572E differential signals MDQS/$\overline{\text{MDQS}}$ and MCK/$\overline{\text{MCK}}$ when in DDR2 mode.

Table 19. DDR2 SDRAM Differential Electrical Characteristics

Parameter/Condition	Symbol	Min	Max	Unit	Notes
DC Input Signal Voltage	V_{IN}	–0.3	GV_{DD} + 0.3	V	—
DC Differential Input Voltage	V_{ID}	—	—	mV	—
AC Differential Input Voltage	V_{IDAC}	—	—	mV	—
DC Differential Output Voltage	V_{OH}	—	—	mV	—
AC Differential Output Voltage	V_{OHAC}	JEDEC: 0.5	JEDEC: GV_{DD} + 0.6	V	—
AC Differential Cross-point Voltage	V_{IXAC}	—	—	mV	—
Input Midpoint Voltage	V_{MP}	—	—	mV	—

Figure 14 shows the MII receive AC timing diagram.

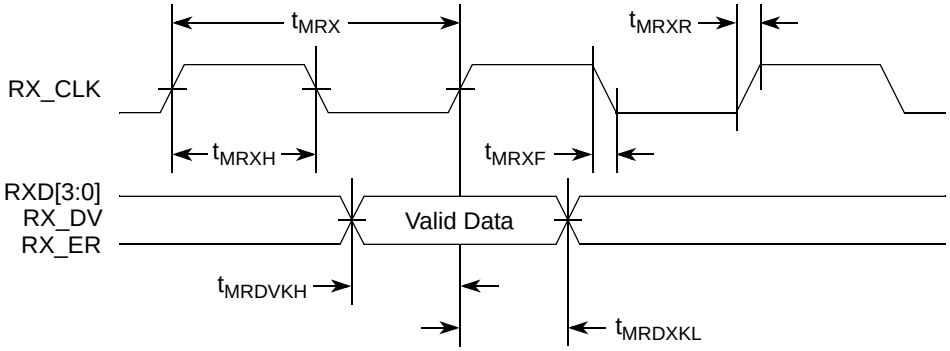


Figure 14. MII Receive AC Timing Diagram

8.2.4 TBI AC Timing Specifications

This section describes the TBI transmit and receive AC timing specifications.

8.2.4.1 TBI Transmit AC Timing Specifications

Table 31 provides the TBI transmit AC timing specifications.

Table 31. TBI Transmit AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
TCG[9:0] setup time GTX_CLK going high	t_{TTKHDV}	2.0	—	—	ns
TCG[9:0] hold time from GTX_CLK going high	t_{TTKHDX}	1.0	—	—	ns
GTX_CLK rise (20%–80%)	t_{TTXR}[2]	—	—	1.0	ns
GTX_CLK fall time (80%–20%)	t_{TTXF}[2]	—	—	1.0	ns

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{TTKHDV} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the valid state (V) or setup time. Also, t_{TTKHDX} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the invalid state (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TTX} represents the TBI (T) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Guaranteed by design.

Table 42. eTSEC IEEE 1588 AC Timing Specifications (continued)

At recommended operating conditions with LV_{DD}/TV_{DD} of 3.3 V ± 5% or 2.5 V ± 5%

Parameter/Condition	Symbol	Min	Typ	Max	Unit	Note
TSEC_1588_CLK_OUT duty cycle	$t_{T1588CLKOTH}$ /$t_{T1588CLKOUT}$	30	50	70	%	—
TSEC_1588_PULSE_OUT	$t_{T1588OV}$	0.5	—	3.0	ns	—
TSEC_1588_TRIG_IN pulse width	$t_{T1588TRIGH}$	$2*t_{T1588CLK\_MAX}$	—	—	ns	2

Note:

1. When TMR_CTRL[CKSEL] is set as '00', the external TSEC_1588_CLK input is selected as the 1588 timer reference clock source, with the timing defined in Table 42, "eTSEC IEEE 1588 AC Timing Specifications." The maximum value of $t_{T1588CLK}$ is defined in terms of T_{TX_CLK}, that is the maximum clock cycle period of the equivalent interface speed that the eTSEC1 port is running at. When eTSEC1 is configured to operate in the parallel mode, the T_{TX_CLK} is the maximum clock period of the TSEC1_TX_CLK. When eTSEC1 operates in SGMII mode, the maximum value of $t_{T1588CLK}$ is defined in terms of the recovered clock from SGMII SerDes. For example, for SGMII 10/100/1000 Mbps modes, the maximum value of $t_{T1588CLK}$ is 3600, 360, 72 ns respectively. See the *MPC8572E PowerQUICC™ III Integrated Communications Processor Reference Manual* for detailed description of TMR_CTRL registers.
2. It needs to be at least two times of the clock period of the clock selected by TMR_CTRL[CKSEL].

9 Ethernet Management Interface Electrical Characteristics

The electrical characteristics specified here apply to MII management interface signals ECn_MDIO (management data input/output) and ECn_MDC (management data clock). The electrical characteristics for GMII, SGMII, RGMII, RMII, TBI and RTBI are specified in "Section 8, "Ethernet: Enhanced Three-Speed Ethernet (eTSEC)."

9.1 MII Management DC Electrical Characteristics

The ECn_MDC and ECn_MDIO are defined to operate at a supply voltage of 3.3 V or 2.5 V. The DC electrical characteristics for ECn_MDIO and ECn_MDC are provided in Table 43 and Table 44.

Table 43. MII Management DC Electrical Characteristics (LV_{DD}/TV_{DD}=3.3 V)

Parameter	Symbol	Min	Max	Unit	Notes
Supply voltage (3.3 V)	LV_{DD}/TV_{DD}	3.13	3.47	V	1, 2
Output high voltage (LV_{DD}/TV_{DD} = Min, I_{OH} = –1.0 mA)	V_{OH}	2.10	OV_{DD} + 0.3	V	—
Output low voltage (LV_{DD}/TV_{DD} =Min, I_{OL} = 1.0 mA)	V_{OL}	GND	0.50	V	—
Input high voltage	V_{IH}	2.0	—	V	—
Input low voltage	V_{IL}	—	0.90	V	—
Input high current (LV_{DD}/TV_{DD} = Max, V_{IN} [3] = 2.1 V)	I_{IH}	—	40	µA	—

11 Programmable Interrupt Controller

In IRQ edge trigger mode, when an external interrupt signal is asserted (according to the programmed polarity), it must remain asserted for at least 3 system clocks (SYSCLK periods).

12 JTAG

This section describes the AC electrical specifications for the IEEE 1149.1 (JTAG) interface of the MPC8572E.

Table 53 provides the JTAG AC timing specifications as defined in Figure 37 through Figure 39.

Table 53. JTAG AC Timing Specifications (Independent of SYSCLK) [1]

At recommended operating conditions with OV_{DD} of 3.3 V ± 5%.

Parameter	Symbol [2]	Min	Max	Unit	Notes
JTAG external clock frequency of operation	f_{JTG}	0	33.3	MHz	—
JTAG external clock cycle time	t_{JTG}	30	—	ns	—
JTAG external clock pulse width measured at 1.4 V	t_{JTKHKL}	15	—	ns	—
JTAG external clock rise and fall times	t_{JTGR} & t_{JTGF}	0	2	ns	6
$\overline{\text{TRST}}$ assert time	t_{TRST}	25	—	ns	3
Input setup times: Boundary-scan data TMS, TDI	 t_{JTDVKH} t_{JTIVKH}	 4 0	 — —	ns	4
Input hold times: Boundary-scan data TMS, TDI	 t_{JTDXKH} t_{JTIXKH}	 20 25	 — —	ns	4
Valid times: Boundary-scan data TDO	 t_{JTKLDV} t_{JTKLOV}	 4 4	 20 25	ns	5
Output hold times: Boundary-scan data TDO	 t_{JTKLDX} t_{JTKLOX}	 30 30	 — —	ns	5

15 High-Speed Serial Interfaces (HSSI)

The MPC8572E features two Serializer/Deserializer (SerDes) interfaces to be used for high-speed serial interconnect applications. The SerDes1 interface can be used for PCI Express and/or Serial RapidIO data transfers. The SerDes2 is dedicated for SGMII application.

This section describes the common portion of SerDes DC electrical specifications, which is the DC requirement for SerDes Reference Clocks. The SerDes data lane's transmitter and receiver reference circuits are also shown.

15.1 Signal Terms Definition

The SerDes utilizes differential signaling to transfer data across the serial link. This section defines terms used in the description and specification of differential signals.

Figure 43 shows how the signals are defined. For illustration purpose, only one SerDes lane is used for description. The figure shows waveform for either a transmitter output (SDn_TX and $\overline{\text{SDn\_TX}}$) or a receiver input (SDn_RX and $\overline{\text{SDn\_RX}}$). Each signal swings between A Volts and B Volts where A > B.

Using this waveform, the definitions are as follows. To simplify illustration, the following definitions assume that the SerDes transmitter and receiver operate in a fully symmetrical differential signaling environment.

1. **Single-Ended Swing**

   The transmitter output signals and the receiver input signals SDn_TX, $\overline{\text{SDn\_TX}}$, SDn_RX and $\overline{\text{SDn\_RX}}$ each have a peak-to-peak swing of A - B Volts. This is also referred as each signal wire's Single-Ended Swing.

2. **Differential Output Voltage, V_{OD}** (or **Differential Output Swing**):

   The Differential Output Voltage (or Swing) of the transmitter, V_{OD}, is defined as the difference of the two complimentary output voltages: $V_{SDn\_TX} - V_{\overline{SDn\_TX}}$. The V_{OD} value can be either positive or negative.

3. **Differential Input Voltage, V_{ID}** (or **Differential Input Swing**):

   The Differential Input Voltage (or Swing) of the receiver, V_{ID}, is defined as the difference of the two complimentary input voltages: $V_{SDn\_RX} - V_{\overline{SDn\_RX}}$. The V_{ID} value can be either positive or negative.

4. **Differential Peak Voltage, V_{DIFFp}**

   The peak value of the differential transmitter output signal or the differential receiver input signal is defined as Differential Peak Voltage, $V_{DIFFp} = |A - B|$ Volts.

5. **Differential Peak-to-Peak, $V_{DIFFp-p}$**

   Because the differential output signal of the transmitter and the differential input signal of the receiver each range from A – B to –(A – B) Volts, the peak-to-peak value of the differential transmitter output signal or the differential receiver input signal is defined as Differential Peak-to-Peak Voltage, $V_{DIFFp-p} = 2*V_{DIFFp} = 2 * |(A - B)|$ Volts, which is twice of differential swing in amplitude, or twice of the differential peak. For example, the output differential peak-peak voltage can also be calculated as $V_{TX-DIFFp-p} = 2*|V_{OD}|$.

is less of a problem. Phase noise above 15MHz is filtered by the PLL. The most problematic phase noise occurs in the 1-15MHz range. The source impedance of the clock driver should be 50 ohms to match the transmission line and reduce reflections which are a source of noise to the system.

Table 60 describes some AC parameters common to SGMII, PCI Express and Serial RapidIO protocols.

Table 60. SerDes Reference Clock Common AC Parameters

At recommended operating conditions with XV_{DD_SRDS1} or XV_{DD_SRDS2} = 1.1V ± 5%.

Parameter	Symbol	Min	Max	Unit	Notes
Rising Edge Rate	Rise Edge Rate	1.0	4.0	V/ns	2, 3
Falling Edge Rate	Fall Edge Rate	1.0	4.0	V/ns	2, 3
Differential Input High Voltage	V_{IH}	+200		mV	2
Differential Input Low Voltage	V_{IL}	—	-200	mV	2
Rising edge rate (SDn_REF_CLK) to falling edge rate (SDn_REF_CLK) matching	Rise-Fall Matching	—	20	%	1, 4

Notes:

1. Measurement taken from single ended waveform.
2. Measurement taken from differential waveform.
3. Measured from -200 mV to +200 mV on the differential waveform (derived from SDn_REF_CLK minus $\overline{\text{SDn\_REF\_CLK}}$). The signal must be monotonic through the measurement region for rise and fall time. The 400 mV measurement window is centered on the differential zero crossing. See Figure 52.
4. Matching applies to rising edge rate for SDn_REF_CLK and falling edge rate for $\overline{\text{SDn\_REF\_CLK}}$. It is measured using a 200 mV window centered on the median cross point where SDn_REF_CLK rising meets $\overline{\text{SDn\_REF\_CLK}}$ falling. The median cross point is used to calculate the voltage thresholds the oscilloscope is to use for the edge rate calculations. The Rise Edge Rate of SDn_REF_CLK should be compared to the Fall Edge Rate of $\overline{\text{SDn\_REF\_CLK}}$, the maximum allowed difference should not exceed 20% of the slowest edge rate. See Figure 53.

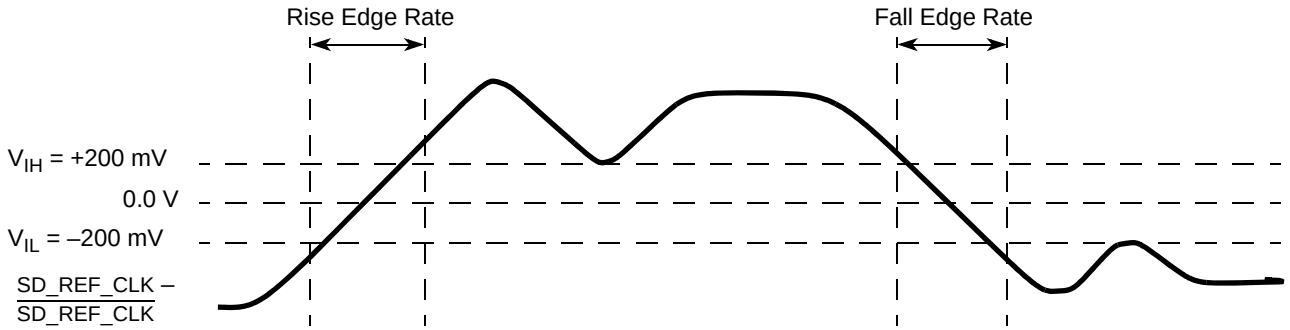


Figure 52. Differential Measurement Points for Rise and Fall Time

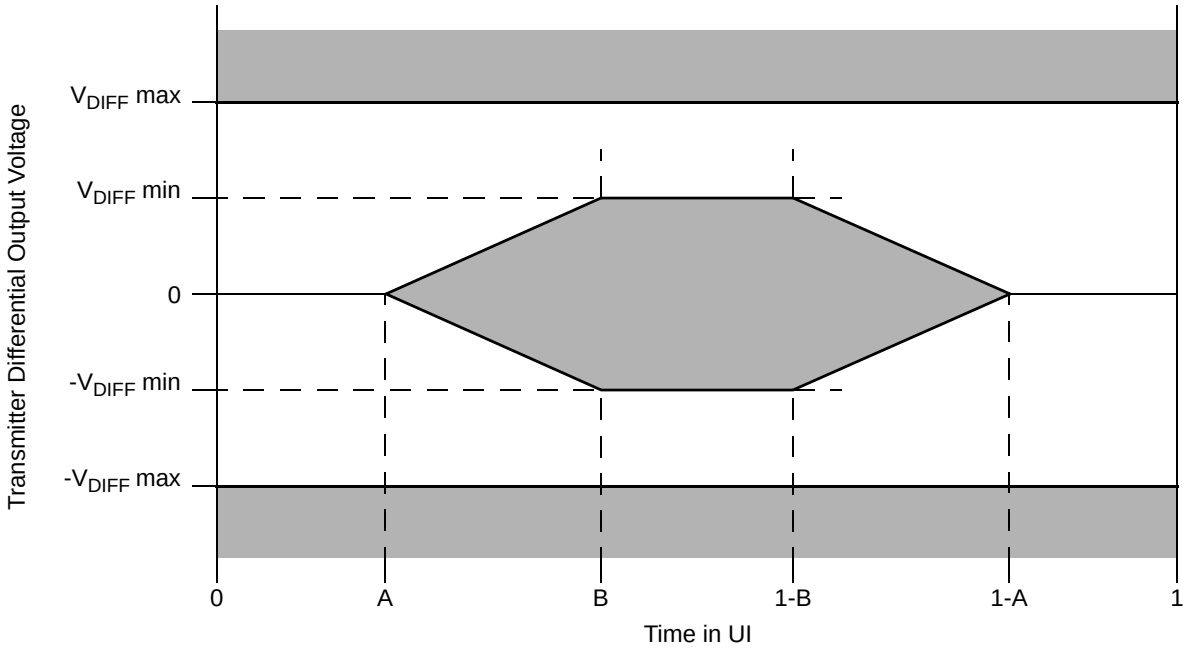


Figure 58. Transmitter Output Compliance Mask

Table 71. Transmitter Differential Output Eye Diagram Parameters

Transmitter Type	V_{DIFF}min (mV)	V_{DIFF}max (mV)	A (UI)	B (UI)
1.25 GBaud short range	250	500	0.175	0.39
1.25 GBaud long range	400	800	0.175	0.39
2.5 GBaud short range	250	500	0.175	0.39
2.5 GBaud long range	400	800	0.175	0.39
3.125 GBaud short range	250	500	0.175	0.39
3.125 GBaud long range	400	800	0.175	0.39

17.6 Receiver Specifications

LP-Serial receiver electrical and timing specifications are stated in the text and tables of this section.

Receiver input impedance shall result in a differential return loss better that 10 dB and a common mode return loss better than 6 dB from 100 MHz to (0.8) × (Baud Frequency). This includes contributions from on-chip circuitry, the chip package and any off-chip components related to the receiver. AC coupling components are included in this requirement. The reference impedance for return loss measurements is 100 Ohm resistive for differential return loss and 25-Ω resistive for common mode.

Table 72. Receiver AC Timing Specifications—1.25 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential Input Voltage	V_{IN}	200	1600	mV p-p	Measured at receiver
Deterministic Jitter Tolerance	J_D	0.37	—	UI p-p	Measured at receiver
Combined Deterministic and Random Jitter Tolerance	J_{DR}	0.55	—	UI p-p	Measured at receiver
Total Jitter Tolerance[1]	J_T	0.65	—	UI p-p	Measured at receiver
Multiple Input Skew	S_{MI}	—	24	ns	Skew at the receiver input between lanes of a multilane link
Bit Error Rate	BER	—	10^{-12}	—	—
Unit Interval	UI	800	800	ps	+/– 100 ppm

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of Figure 59. The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.

Table 73. Receiver AC Timing Specifications—2.5 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential Input Voltage	V_{IN}	200	1600	mV p-p	Measured at receiver
Deterministic Jitter Tolerance	J_D	0.37	—	UI p-p	Measured at receiver
Combined Deterministic and Random Jitter Tolerance	J_{DR}	0.55	—	UI p-p	Measured at receiver
Total Jitter Tolerance[1]	J_T	0.65	—	UI p-p	Measured at receiver
Multiple Input Skew	S_{MI}	—	24	ns	Skew at the receiver input between lanes of a multilane link
Bit Error Rate	BER	—	10^{-12}	—	—
Unit Interval	UI	400	400	ps	+/– 100 ppm

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of Figure 59. The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.

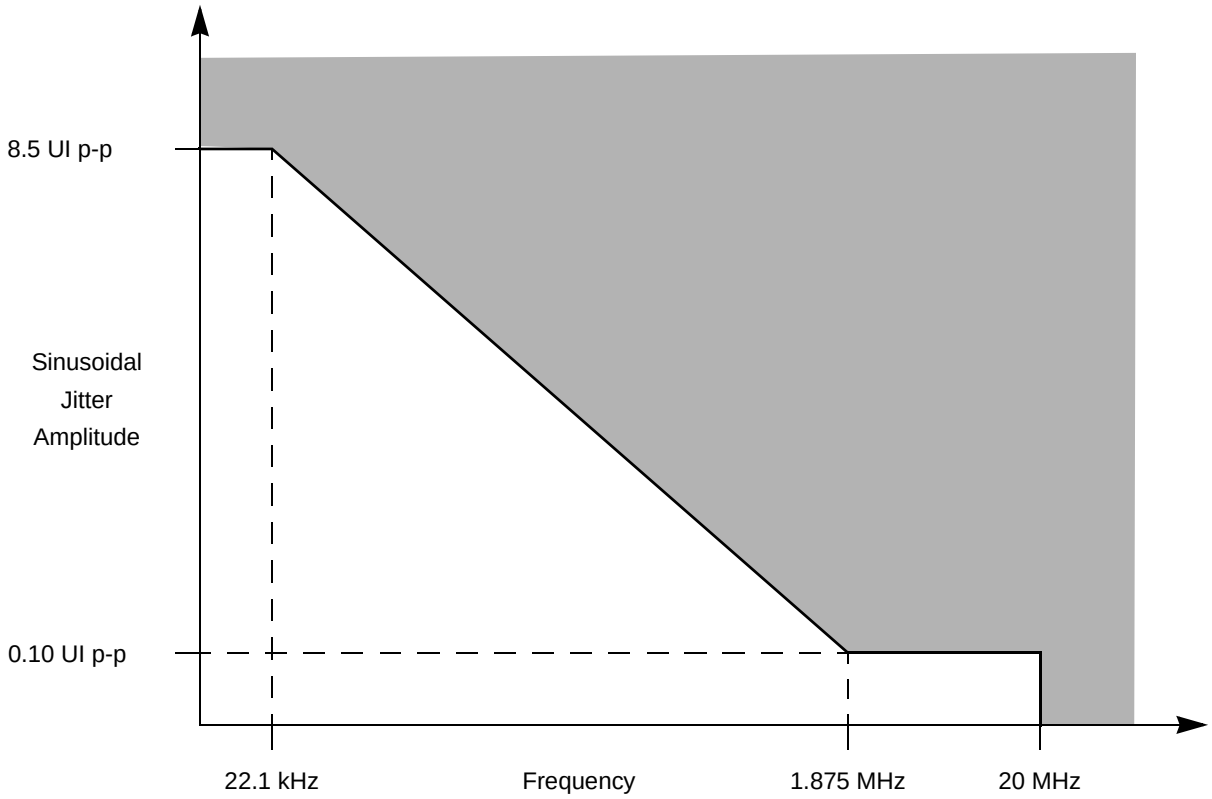


Figure 59. Single Frequency Sinusoidal Jitter Limits

17.7 Receiver Eye Diagrams

For each baud rate at which an LP-Serial receiver is specified to operate, the receiver shall meet the corresponding Bit Error Rate specification (Table 72, Table 73, and Table 74) when the eye pattern of the receiver test signal (exclusive of sinusoidal jitter) falls entirely within the unshaded portion of the Receiver Input Compliance Mask shown in Figure 60 with the parameters specified in Table 75. The eye pattern of the receiver test signal is measured at the input pins of the receiving device with the device replaced with a 100-Ω +/– 5% differential resistive load.

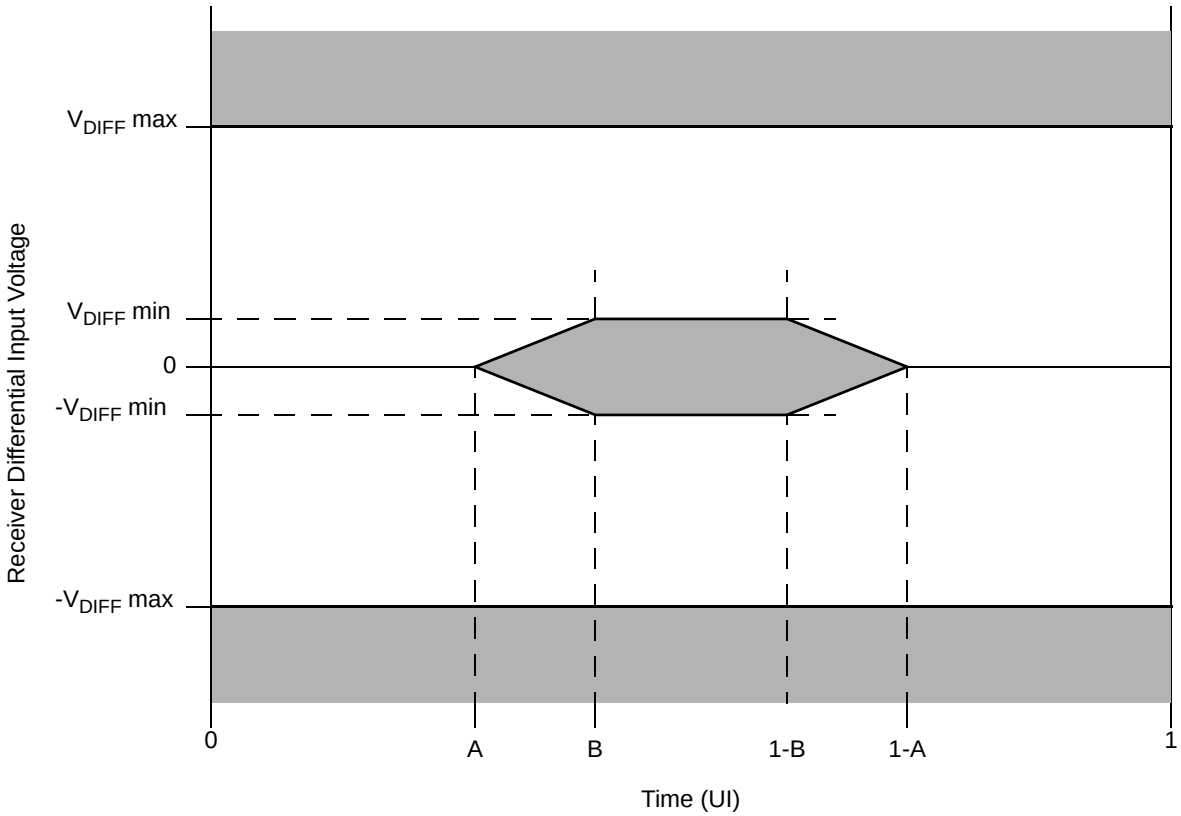


Figure 60. Receiver Input Compliance Mask

Table 75. Receiver Input Compliance Mask Parameters Exclusive of Sinusoidal Jitter

Receiver Type	V_{DIFF}min (mV)	V_{DIFF}max (mV)	A (UI)	B (UI)
1.25 GBaud	100	800	0.275	0.400
2.5 GBaud	100	800	0.275	0.400
3.125 GBaud	100	800	0.275	0.400

17.8 Measurement and Test Requirements

Because the LP-Serial electrical specification are guided by the XAUI electrical interface specified in Clause 47 of IEEE 802.3ae-2002, the measurement and test requirements defined here are similarly guided by Clause 47. Additionally, the CJPAT test pattern defined in Annex 48A of IEEE 802.3ae-2002 is specified as the test pattern for use in eye pattern and jitter measurements. Annex 48B of IEEE 802.3ae-2002 is recommended as a reference for additional information on jitter test methods.

17.8.1 Eye Template Measurements

For the purpose of eye template measurements, the effects of a single-pole high pass filter with a 3 dB point at (Baud Frequency)/1667 is applied to the jitter. The data pattern for template measurements is the Continuous Jitter Test Pattern (CJPAT) defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-Serial

link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. The amount of data represented in the eye shall be adequate to ensure that the bit error ratio is less than 10^{-12}. The eye pattern shall be measured with AC coupling and the compliance template centered at 0 Volts differential. The left and right edges of the template shall be aligned with the mean zero crossing points of the measured data eye. The load for this test shall be 100 Ω resistive +/– 5% differential to 2.5 GHz.

17.8.2 Jitter Test Measurements

For the purpose of jitter measurement, the effects of a single-pole high pass filter with a 3 dB point at (Baud Frequency)/1667 is applied to the jitter. The data pattern for jitter measurements is the Continuous Jitter Test Pattern (CJPAT) pattern defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-Serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. Jitter shall be measured with AC coupling and at 0 Volts differential. Jitter measurement for the transmitter (or for calibration of a jitter tolerance setup) shall be performed with a test procedure resulting in a BER curve such as that described in Annex 48B of IEEE 802.3ae.

17.8.3 Transmit Jitter

Transmit jitter is measured at the driver output when terminated into a load of 100 Ω resistive +/– 5% differential to 2.5 GHz.

17.8.4 Jitter Tolerance

Jitter tolerance is measured at the receiver using a jitter tolerance test signal. This signal is obtained by first producing the sum of deterministic and random jitter defined in Section 17.6, “Receiver Specifications,” and then adjusting the signal amplitude until the data eye contacts the 6 points of the minimum eye opening of the receive template shown in Figure 60 and Table 75. Note that for this to occur, the test signal must have vertical waveform symmetry about the average value and have horizontal symmetry (including jitter) about the mean zero crossing. Eye template measurement requirements are as defined above. Random jitter is calibrated using a high pass filter with a low frequency corner at 20 MHz and a 20 dB/decade roll-off below this. The required sinusoidal jitter specified in Section 17.6, “Receiver Specifications,” is then added to the signal and the test load is replaced by the receiver being tested.

18 Package Description

This section describes package parameters, pin assignments, and dimensions.

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
D2_MBA[0:2]	Bank Select	Y1, W3, P3	O	GV_{DD}	—
$\overline{\text{D2\_MWE}}$	Write Enable	AA2	O	GV_{DD}	—
$\overline{\text{D2\_MCAS}}$	Column Address Strobe	AD1	O	GV_{DD}	—
$\overline{\text{D2\_MRAS}}$	Row Address Strobe	AA1	O	GV_{DD}	—
D2_MCKE[0:3]	Clock Enable	L3, L1, K1, K2	O	GV_{DD}	11
$\overline{\text{D2\_MCS}}$[0:3]	Chip Select	AB1, AG2, AC1, AH2	O	GV_{DD}	—
D2_MCK[0:5]	Clock	V4, F7, AJ3, V2, E7, AG4	O	GV_{DD}	—
$\overline{\text{D2\_MCK}}$[0:5]	Clock Complements	V1, F8, AJ4, U1, E6, AG5	O	GV_{DD}	—
D2_MODT[0:3]	On Die Termination	AE1, AG1, AE2, AH1	O	GV_{DD}	—
D2_MDIC[0:1]	Driver Impedance Calibration	F1, G1	I/O	GV_{DD}	25
Local Bus Controller Interface					
LAD[0:31]	Muxed Data/Address	M22, L22, F22, G22, F21, G21, E20, H22, K22, K21, H19, J20, J19, L20, M20, M19, E22, E21, L19, K19, G19, H18, E18, G18, J17, K17, K14, J15, H16, J14, H15, G15	I/O	BV_{DD}	34
LDP[0:3]	Data Parity	M21, D22, A24, E17	I/O	BV_{DD}	—
LA[27]	Burst Address	J21	O	BV_{DD}	5, 9
LA[28:31]	Port Address	F20, K18, H20, G17	O	BV_{DD}	5, 7, 9
$\overline{\text{LCS}}$[0:4]	Chip Selects	B23, E16, D20, B25, A22	O	BV_{DD}	10
$\overline{\text{LCS}}$[5]/$\overline{\text{DMA2\_DREQ}}$[1]	Chip Selects / DMA Request	D19	I/O	BV_{DD}	1, 10
$\overline{\text{LCS}}$[6]/$\overline{\text{DMA2\_DACK}}$[1]	Chip Selects / DMA Ack	E19	O	BV_{DD}	1, 10
$\overline{\text{LCS}}$[7]/$\overline{\text{DMA2\_DDONE}}$[1]	Chip Selects / DMA Done	C21	O	BV_{DD}	1, 10
$\overline{\text{LWE}}$[0]/$\overline{\text{LBS}}$[0]/$\overline{\text{LFWE}}$	Write Enable / Byte Select	D17	O	BV_{DD}	5, 9
$\overline{\text{LWE}}$[1]/$\overline{\text{LBS}}$[1]	Write Enable / Byte Select	F15	O	BV_{DD}	5, 9
$\overline{\text{LWE}}$[2]/$\overline{\text{LBS}}$[2]	Write Enable / Byte Select	B24	O	BV_{DD}	5, 9
$\overline{\text{LWE}}$[3]/$\overline{\text{LBS}}$[3]	Write Enable / Byte Select	D18	O	BV_{DD}	5, 9
LALE	Address Latch Enable	F19	O	BV_{DD}	5, 8, 9
LBCTL	Buffer Control	L18	O	BV_{DD}	5, 8, 9

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
LGPL0/LFCLE	UPM General Purpose Line 0 / Flash Command Latch Enable	J13	O	BV_{DD}	5, 9
LGPL1/$\overline{\text{LFALE}}$	UPM General Purpose Line 1/ Flash Address Latch Enable	J16	O	BV_{DD}	5, 9
LGPL2/$\overline{\text{LOE}}$/$\overline{\text{LFRE}}$	UPM General Purpose Line 2 / Output Enable / Flash Read Enable	A27	O	BV_{DD}	5, 8, 9
LGPL3/$\overline{\text{LFWP}}$	UPM General Purpose Line 3 / Flash Write Protect	K16	O	BV_{DD}	5, 9
LGPL4/$\overline{\text{LGTA}}$/LUPWAIT/LPBSE/LFRB	UPM General Purpose Line 4 / Target Ack / Wait / Parity Byte Select / Flash Ready-Busy	L17	I/O	BV_{DD}	—
LGPL5	UPM General Purpose Line 5 / Amux	B26	O	BV_{DD}	5, 9
LCLK[0:2]	Local Bus Clock	F17, F16, A23	O	BV_{DD}	—
LSYNC_IN	Local Bus DLL Synchronization	B22	I	BV_{DD}	—
LSYNC_OUT	Local Bus DLL Synchronization	A21	O	BV_{DD}	—
DMA					
$\overline{\text{DMA1\_DACK}}$[0:1]	DMA Acknowledge	W25, U30	O	OV_{DD}	21
$\overline{\text{DMA2\_DACK}}$[0]	DMA Acknowledge	AA26	O	OV_{DD}	5, 9
$\overline{\text{DMA1\_DREQ}}$[0:1]	DMA Request	Y29, V27	I	OV_{DD}	—
$\overline{\text{DMA2\_DREQ}}$[0]	DMA Request	V29	I	OV_{DD}	—
$\overline{\text{DMA1\_DDONE}}$[0:1]	DMA Done	Y28, V30	O	OV_{DD}	5, 9
$\overline{\text{DMA2\_DDONE}}$[0]	DMA Done	AA28	O	OV_{DD}	5, 9
$\overline{\text{DMA2\_DREQ}}$[2]	DMA Request	M23	I	BV_{DD}	—
Programmable Interrupt Controller					
$\overline{\text{UDE0}}$	Unconditional Debug Event Processor 0	AC25	I	OV_{DD}	—
$\overline{\text{UDE1}}$	Unconditional Debug Event Processor 1	AA25	I	OV_{DD}	—
$\overline{\text{MCP0}}$	Machine Check Processor 0	M28	I	OV_{DD}	—
$\overline{\text{MCP1}}$	Machine Check Processor 1	L28	I	OV_{DD}	—
IRQ[0:11]	External Interrupts	T24, R24, R25, R27, R28, AB27, AB28, P27, R30, AC28, R29, T31	I	OV_{DD}	—

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{IRQ\_OUT}}$	Interrupt Output	U24	O	OV_{DD}	2, 4
1588					
TSEC_1588_CLK	Clock In	AM22	I	LV_{DD}	—
TSEC_1588_TRIG_IN	Trigger In	AM23	I	LV_{DD}	—
TSEC_1588_TRIG_OUT	Trigger Out	AA23	O	LV_{DD}	5, 9
TSEC_1588_CLK_OUT	Clock Out	AC23	O	LV_{DD}	5, 9
TSEC_1588_PULSE_OUT1	Pulse Out1	AA22	O	LV_{DD}	5, 9
TSEC_1588_PULSE_OUT2	Pulse Out2	AB23	O	LV_{DD}	5, 9
Ethernet Management Interface 1					
EC1_MDC	Management Data Clock	AL30	O	LV_{DD}	5, 9
EC1_MDIO	Management Data In/Out	AM25	I/O	LV_{DD}	—
Ethernet Management Interface 3					
EC3_MDC	Management Data Clock	AF19	O	TV_{DD}	5, 9
EC3_MDIO	Management Data In/Out	AF18	I/O	TV_{DD}	—
Ethernet Management Interface 5					
EC5_MDC	Management Data Clock	AF14	O	TV_{DD}	21
EC5_MDIO	Management Data In/Out	AF15	I/O	TV_{DD}	—
Gigabit Ethernet Reference Clock					
EC_GTX_CLK125	Reference Clock	AM24	I	LV_{DD}	32
Three-Speed Ethernet Controller 1					
TSEC1_RXD[7:0]/FIFO1_RXD[7:0]	Receive Data	AM28, AL28, AM26, AK23, AM27, AK26, AL29, AM30	I	LV_{DD}	1
TSEC1_TXD[7:0]/FIFO1_TXD[7:0]	Transmit Data	AC20, AD20, AE22, AB22, AC22, AD21, AB21, AE21	O	LV_{DD}	1, 5, 9
TSEC1_COL/FIFO1_TX_FC	Collision Detect/Flow Control	AJ23	I	LV_{DD}	1
TSEC1_CRS/FIFO1_RX_FC	Carrier Sense/Flow Control	AM31	I/O	LV_{DD}	1, 16
TSEC1_GTX_CLK	Transmit Clock Out	AK27	O	LV_{DD}	
TSEC1_RX_CLK/FIFO1_RX_CLK	Receive Clock	AL25	I	LV_{DD}	1

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
SD1_RX[7:0]	Receive Data (positive)	P32, N30, M32, L30, G30, F32, E30, D32	I	XV_{DD_SRDS1}	—
$\overline{\text{SD1\_RX}}$[7:0]	Receive Data (negative)	P31, N29, M31, L29, G29, F31, E29, D31	I	XV_{DD_SRDS1}	—
SD1_TX[7]	PCIe1 Tx Data Lane 7 / SRIO or PCIe2 Tx Data Lane 3 / PCIe3 TX Data Lane 1	M26	O	XV_{DD_SRDS1}	—
SD1_TX[6]	PCIe1 Tx Data Lane 6 / SRIO or PCIe2 Tx Data Lane 2 / PCIe3 TX Data Lane 0	L24	O	XV_{DD_SRDS1}	—
SD1_TX[5]	PCIe1 Tx Data Lane 5 / SRIO or PCIe2 Tx Data Lane 1	K26	O	XV_{DD_SRDS1}	—
SD1_TX[4]	PCIe1 Tx Data Lane 4 / SRIO or PCIe2 Tx Data Lane 0	J24	O	XV_{DD_SRDS1}	—
SD1_TX[3]	PCIe1 Tx Data Lane 3	G24	O	XV_{DD_SRDS1}	—
SD1_TX[2]	PCIe1 Tx Data Lane 2	F26	O	XV_{DD_SRDS1}	—
SD1_TX[1]	PCIe1 Tx Data Lane 1]	E24	O	XV_{DD_SRDS1}	—
SD1_TX[0]	PCIe1 Tx Data Lane 0	D26	O	XV_{DD_SRDS1}	—
$\overline{\text{SD1\_TX}}$[7:0]	Transmit Data (negative)	M27, L25, K27, J25, G25, F27, E25, D27	O	XV_{DD_SRDS1}	—
SD1_PLL_TPD	PLL Test Point Digital	J32	O	XV_{DD_SRDS1}	17
SD1_REF_CLK	PLL Reference Clock	H32	I	XV_{DD_SRDS1}	—
$\overline{\text{SD1\_REF\_CLK}}$	PLL Reference Clock Complement	H31	I	XV_{DD_SRDS1}	—
Reserved	—	C29, K32	—	—	26
Reserved	—	C30, K31	—	—	27
Reserved	—	C24, C25, H26, H27	—	—	28
Reserved	—	AL20, AL21	—	—	29
SerDes (x4) SGMII					
SD2_RX[3:0]	Receive Data (positive)	AK32, AJ30, AF30, AE32	I	XV_{DD_SRDS2}	—

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
SD1_IMP_CAL_RX	SerDes1 Rx Impedance Calibration	B32	I	200Ω (±1%) to GND	—
SD1_IMP_CAL_TX	SerDes1 Tx Impedance Calibration	T32	I	100Ω (±1%) to GND	—
SD1_PLL_TPA	SerDes1 PLL Test Point Analog	J30	O	AVDD_SRDS analog	17
SD2_IMP_CAL_RX	SerDes2 Rx Impedance Calibration	AC32	I	200Ω (±1%) to GND	—
SD2_IMP_CAL_TX	SerDes2 Tx Impedance Calibration	AM32	I	100Ω (±1%) to GND	—
SD2_PLL_TPA	SerDes2 PLL Test Point Analog	AH30	O	AVDD_SRDS analog	17
TEMP_ANODE	Temperature Diode Anode	AA31	—	internal diode	14
TEMP_CATHODE	Temperature Diode Cathode	AB31	—	internal diode	14
No Connection Pins					

21 System Design Information

This section provides electrical and thermal design recommendations for successful application of the MPC8572E.

21.1 System Clocking

The platform PLL generates the platform clock from the externally supplied SYSCLK input. The frequency ratio between the platform and SYSCLK is selected using the platform PLL ratio configuration bits as described in Section 19.2, "CCB/SYSCLK PLL Ratio." The MPC8572E includes seven PLLs, with the following functions:

- Two core PLLs have ratios that are individually configurable. Each e500 core PLL generates the core clock as a slave to the platform clock. The frequency ratio between the e500 core clock and the platform clock is selected using the e500 PLL ratio configuration bits as described in Section 19.3, "e500 Core PLL Ratio."
- The DDR complex PLL generates the clocking for the DDR controllers.
- The local bus PLL generates the clock for the local bus.
- The PLL for the SerDes1 module is used for PCI Express and Serial Rapid IO interfaces.
- The PLL for the SerDes2 module is used for the SGMII interface.

21.2 Power Supply Design

21.2.1 PLL Power Supply Filtering

Each of the PLLs listed above is provided with power through independent power supply pins (AV_{DD}_PLAT, AV_{DD}_CORE0, AV_{DD}_CORE1, AV_{DD}_DDR, AV_{DD}_LBIU, AV_{DD}_SRDS1 and AV_{DD}_SRDS2 respectively). The AV_{DD} level should always be equivalent to V_{DD}, and preferably these voltages are derived directly from V_{DD} through a low frequency filter scheme such as the following.

There are a number of ways to reliably provide power to the PLLs, but the recommended solution is to provide independent filter circuits per PLL power supply as illustrated in Figure 62, one to each of the AV_{DD} pins. By providing independent filters to each PLL the opportunity to cause noise injection from one PLL to the other is reduced.

This circuit is intended to filter noise in the PLLs resonant frequency range from a 500 kHz to 10 MHz range. It should be built with surface mount capacitors with minimum Effective Series Inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

Each circuit should be placed as close as possible to the specific AV_{DD} pin being supplied to minimize noise coupled from nearby circuits. It should be possible to route directly from the capacitors to the AV_{DD} pin, which is on the periphery of the 1023 FC-PBGA footprint, without the inductance of vias.

logic does not interfere with normal chip operation. While the TAP controller can be forced to the reset state using only the TCK and TMS signals, generally systems assert $\overline{\text{TRST}}$ during the power-on reset flow. Simply tying $\overline{\text{TRST}}$ to $\overline{\text{HRESET}}$ is not practical because the JTAG interface is also used for accessing the common on-chip processor (COP), which implements the debug interface to the chip.

The COP function of these processors allow a remote computer system (typically, a PC with dedicated hardware and debugging software) to access and control the internal operations of the processor. The COP interface connects primarily through the JTAG port of the processor, with some additional status monitoring signals. The COP port requires the ability to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$ to fully control the processor. If the target system has independent reset sources, such as voltage monitors, watchdog timers, power supply failures, or push-button switches, then the COP reset signals must be merged into these signals with logic.

The arrangement shown in Figure 66 allows the COP port to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$, while ensuring that the target can drive $\overline{\text{HRESET}}$ as well.

The COP interface has a standard header, shown in Figure 65, for connection to the target system, and is based on the 0.025" square-post, 0.100" centered header assembly (often called a Berg header). The connector typically has pin 14 removed as a connector key.

The COP header adds many benefits such as breakpoints, watchpoints, register and memory examination/modification, and other standard debugger features. An inexpensive option can be to leave the COP header unpopulated until needed.

There is no standardized way to number the COP header; so emulator vendors have issued many different pin numbering schemes. Some COP headers are numbered top-to-bottom then left-to-right, while others use left-to-right then top-to-bottom. Still others number the pins counter-clockwise from pin 1 (as with an IC). Regardless of the numbering scheme, the signal placement recommended in Figure 65 is common to all known emulators.

21.9.1 Termination of Unused Signals

If the JTAG interface and COP header is not used, Freescale recommends the following connections:

- $\overline{\text{TRST}}$ should be tied to $\overline{\text{HRESET}}$ through a 0 kΩ isolation resistor so that it is asserted when the system reset signal ($\overline{\text{HRESET}}$) is asserted, ensuring that the JTAG scan chain is initialized during the power-on reset flow. Freescale recommends that the COP header be designed into the system as shown in Figure 66. If this is not possible, the isolation resistor allows future access to $\overline{\text{TRST}}$ in case a JTAG interface may need to be wired onto the system in future debug situations.
- No pull-up/pull-down is required for TDI, TMS, TDO or TCK.